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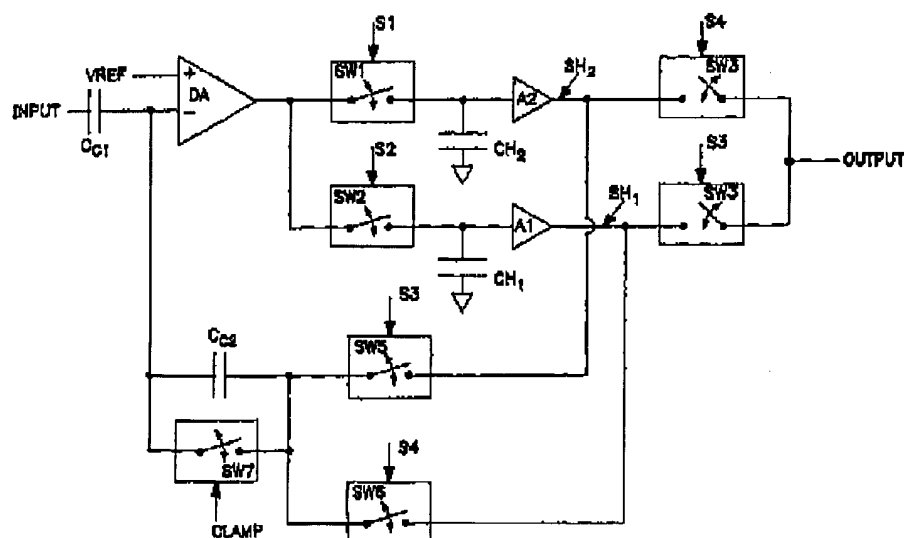
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(54) Title: PIPELINED SAMPLE AND HOLD CIRCUIT WITH CORRELATED DOUBLE SAMPLING



(57) Abstract

A signal sampling circuit for performing correlated double sampling (CDS) of an input signal with a pipelined sample and hold architecture includes a time multiplexed integrating amplifier circuit in which the output circuit is a pipelined sample and hold circuit which provides time multiplexed input signal samples and the feedback integration capacitor is discharged between samples. At all times, one of the channels of the pipelined sample and hold circuit is providing one of the time multiplexed input signal samples while the other channel continues tracking the input signal. The feedback integration capacitor acts as a clamp to null out residual reset noise received as part of the input signal to be sampled. Hence, with the exception of that very brief period of time necessary for switching between the two pipelined sample and hold circuit channels, one of the two pipelined sample and hold circuit channels is always available for signal acquisition.

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PIPELINED SAMPLE AND HOLD CIRCUIT WITH CORRELATED DOUBLE SAMPLING

FIELD OF THE INVENTION

The present invention relates to sample and hold circuits, and in particular, to pipelined sample and hold circuits with correlated double sampling.

BACKGROUND OF THE INVENTION

Sample and hold circuits play an important role in data acquisition systems, particularly in those systems in which the signals containing the data of interest are changing faster than the system can acquire and appropriately process the data.

For example, in large area, flat panel imaging systems, such as imaging systems for medical
10 and document imaging applications based upon amorphous silicon, the image sensor is typically arranged as an array of pixels, each of which consists of a photosensitive element and a thin film transistor (TFT). In order to achieve imaging frame rates suitable for video processing and display, all gate and data line connections for the sensor are brought out to the edge of the array for connection to an off-array control circuit containing row selection and charge sensing circuitry.

15 For a high resolution array, many pixels are used for each data line, with the result being a high data readout rate in order to sample each of the pixels within the time constraints of the real time video display. Accordingly, while the data for each pixel must be sampled accurately, it must also be sampled quickly and held available for a sufficient period of time to allow the pixel data to be appropriately processed, stored, etc.

20 However, such image data signals, due to the manner in which they are generated, include, in addition to the image component, a noise component which is generated as a result of the image array scanning process. For example, the circuitry used to acquire the image data information from each pixel typically includes a charge sensitive pre-amplifier which must be reset between each pixel. This resetting of the charge sensitive pre-amplifier immediately prior to reading out the
25 charge from each pixel generates a significant, and undesirable, noise component which, if not eliminated during the sample and hold process, will significantly distort and obscure the true image information corresponding to that pixel.

Accordingly, it would be desirable to have a sample and hold circuit which is capable of eliminating the noise component from the signal to be sampled.

SUMMARY OF THE INVENTION

In accordance with the present invention, correlated double sampling (CDS) is provided in a pipelined sample and hold circuit architecture. Such a circuit can be used advantageously in multiple channel, charge sensitive readout circuits in which multiple data channels of a sensor are each connected to a charge sensitive pre-amplifier. In such an application, the CDS eliminates the noise associated with resetting the charge sensitive pre-amplifier, while the sample and hold circuitry allows the data from a previous channel to be read out during sampling of the present channel. By using a pipelined sample and hold architecture, maximum data sampling time, or "line time," is available for reading out the sampled data. Hence, only a very small portion of each pixel period is required for data transfer, leaving a significantly larger portion of the pixel period available for the charge sensitive pre-amplifier to acquire new data.

Additionally, multiple pipelined sample and hold circuits with correlated double sampling in accordance with the present invention can be interconnected via an array of switches for purposes of combining, or "binning," data from multiple charge sensitive pre-amplifiers, while providing the CDS function for the resulting composite data signal from the interconnected pre-amplifiers.

More specifically, in accordance with one embodiment of the present invention, a signal sampling circuit for performing correlated double sampling (CDS) of an input signal with a pipelined sample and hold architecture includes a capacitive input circuit, a differential amplifier, a pipelined sample and hold circuit and a capacitive feedback circuit. The capacitive input circuit is configured to receive an input signal, which includes a desired signal component and an undesired signal component, and in accordance therewith provide a capacitively coupled input signal. The differential amplifier is coupled to the capacitive input circuit, includes first and second input terminals and an output terminal, and is configured to receive the capacitively coupled input signal and a reference voltage via the first and second input terminals, respectively, and in accordance therewith provide an amplified input signal via the output terminal. The pipelined sample and hold circuit is coupled to the differential amplifier output terminal and is configured to receive a plurality of sampling control signals and in accordance therewith receive, sample and hold the amplified input signal and in accordance therewith provide first and second pluralities of time multiplexed input signal samples. Respective temporally adjacent ones of the first and second pluralities of time multiplexed input signal samples and temporally coincident ones of the first and second pluralities of time multiplexed input signal samples represent temporally adjacent samples of the input signal.

The capacitive feedback circuit is coupled between the pipelined sample and hold circuit and the first differential amplifier input terminal and is configured to receive a feedback control signal and in accordance therewith receive the first plurality of time multiplexed input signal samples. The first and second pluralities of time multiplexed input signal samples include the desired signal component and exclude the undesired signal component.

In accordance with another embodiment of the present invention, a signal sampling circuit for performing correlated double sampling (CDS) of an input signal with a pipelined sample and hold architecture includes a capacitive input circuit, a differential amplifier, a pipelined sample and hold circuit and a capacitive feedback circuit. The capacitive input circuit is configured to receive an input signal, which includes a desired signal component and an undesired signal component, and in accordance therewith provide a capacitively coupled input signal. The differential amplifier is coupled to the capacitive input circuit, includes first and second input terminals and an output terminal, and is configured to receive the capacitively coupled input signal and a reference voltage via the first and second input terminals, respectively, and in accordance therewith provide an amplified input signal via the output terminal. The pipelined sample and hold circuit is coupled to the differential amplifier output terminal and is configured to receive one or more sampling control signals and in accordance therewith receive, sample and hold the amplified input signal and in accordance therewith provide a plurality of input signal samples and to time multiplex the plurality of input signal samples and in accordance therewith provide a first plurality of time multiplexed input signal samples. Temporally coincident ones of the plurality of input signal samples and temporally adjacent ones of the first plurality of time multiplexed input signal samples represent temporally adjacent samples of the input signal. The capacitive switching feedback circuit is coupled between the pipelined sample and hold circuit and the first differential amplifier input terminal and is configured to receive a plurality of feedback control signals and the plurality of input signal samples and in accordance therewith time multiplex the plurality of input signal samples and in accordance therewith provide a second plurality of time multiplexed input signal samples and to charge and discharge in accordance therewith. The first and second pluralities of time multiplexed input signal samples include the desired signal component and exclude the undesired signal component.

These and other features and advantages of the present invention will be understood upon consideration of the following detailed description of the invention and the accompanying drawings.

BRIEF DESCRIPTION OF THE DRAWINGS

Figure 1 is a schematic diagram of a pipelined sample and hold circuit with correlated double sampling in accordance with one embodiment of the present invention.

5 Figure 2 is a signal timing diagram for the switch control signals of Figure 1.

Figure 3 illustrates the relative timing of the input signals being sampled and held and outputted by the circuit of Figure 1.

Figure 4 illustrates how multiple pipelined sample and hold circuits with correlated double sampling can be interconnected for combining, or "binning," data from multiple charge sensitive
10 pre-amplifiers.

DETAILED DESCRIPTION OF THE INVENTION

Referring to Figure 1, a pipelined sample and hold circuit with correlated double sampling in accordance with one embodiment of the present invention includes a differential amplifier DA, a
15 number of switches SW1-SW7, two shunt capacitors C_{H1} , C_{H2} , two buffer amplifiers A1, A2 and a feedback integration capacitor C_{C2} , interconnected substantially as shown. The noninverting input of the differential amplifier DA is tied to a dc reference voltage V_{REF} , while the inverting input receives a signal which is the sum of the data input signal INPUT received via a series coupling capacitor C_{C1} and a feedback signal received via the feedback capacitor C_{C2} .

20 The input data signal INPUT originates from a charge sensitive pre-amplifier (not shown) which receives pixel data which is read out from an array in serial form. Such pre-amplifier is reset between each pixel, thereby generating, in addition to the desired image information component, a noise component due to resetting of the pre-amplifier immediately prior to the generating of each pixel signal. During such resetting of the pre-amplifier, switch SW7 is closed in accordance with
25 a clamp control signal CLAMP to discharge the feedback capacitor C_{C2} . This results in the feedback loop between the output and inverting input of the differential amplifier DA to be closed, thereby creating a voltage follower circuit. This causes the output of the differential amplifier DA to be equal to the input reference voltage V_{REF} .

Following the resetting of the pre-amplifier, clamping switch SW7 is opened, thereby causing
30 the reset noise to be captured on the input coupling capacitor C_{C1} while allowing the output voltage

of the differential amplifier DA to follow the input signal at its inverting input. Additionally, any offset associated with the resetting operation of the pre-amplifier has now also been removed.

In accordance with switch control signals $s1-s4$, one of the two sample and hold signal paths SH1, SH2 is selected for sampling the output of the differential amplifier DA, while the other path is selected for holding the previously sampled signal level for buffering by its respective buffer amplifier A1/A2 and outputting via its respective output switch SW3/SW4. For example, when sample and hold signal path SH1 is selected, switches SW2 and SW4 are closed and switches SW1 and SW3 are opened and the voltage across hold capacitor C_{H1} tracks the output of the differential amplifier DA. At the end of the tracking time for sample and hold signal path SH1, switches SW2 and SW4 are opened and switches SW1 and SW3 are closed, preferably in that order. At this point, the last value of the output of the differential amplifier DA, minus the pre-amplifier reset noise, is now stored on hold capacitor C_{H1} for buffering by its buffer amplifier A1 and outputting via switch SW3. Meanwhile, the feedback loop through switches SW1 and SW5 is now closed, thereby allowing the voltage across hold capacitor C_{H2} to track the output of the differential amplifier DA.

The above-described clamping, tracking and sampling operation is repeated for the second sampling and hold signal path SH2. Hence, with the exception of those brief periods of time when the feedback capacitor C_{C2} is discharged and the signal switches SW1-SW6 are transitioning between their respective open and closed states, one of the hold capacitors C_{H1} , C_{H2} is tracking the input signal (minus its associated reset noise) while the other hold capacitor is providing the immediately preceding sampled pixel information as the output signal OUTPUT. Accordingly, maximum time is available for signal acquisition.

Referring to Figure 2, the relative timing of the above-discussed reset, clamp and switch control signals can be better understood. As discussed above, during a reset of the pre-amplifier (interval t_b-t_a), the CLAMP signal is asserted to close switch SW7 (interval t_b-t_d) to discharge the feedback integration capacitor C_{C2} . Immediately preceding this (at time t_a), switch control signal $s1$ is de-asserted while, coincidentally with assertion of the CLAMP signal (time t_b), switch control signals $s2$ and $s4$ are asserted and switch control signal $s3$ is de-asserted. Accordingly, switches SW2, SW4 and SW6 are closed and switches SW1, SW3 and SW5 are opened.

Subsequently, and immediately preceding the next reset of the pre-amplifier (time t_e), switch control signal $s2$ is de-asserted and, coincidentally with the next resetting of the pre-amplifier, switch control signals $s1$ and $s3$ are asserted and switch control signal $s4$ is de-asserted. Hence,

in accordance with the foregoing discussion, sample and hold signal path SH1 is used for tracking the input signal (interval t_4 - t_5) while sample and hold signal path SH2 provides the output signal (interval t_5 - t_6). Immediately thereafter (following time t_1), the second sample and hold signal path SH2 follows the input signal, while the first sample and hold signal path SH1 provides the output signal.

Referring to Figure 3, the above-discussed simultaneous sampling and holding by the multiple channels of the pipelined sample and hold circuit can be better understood. For example, during the time interval that the first sample and hold signal path SH1 is sampling the input signal INPUT (interval t_5 - t_6), the second sample and hold signal path SH2 is in its hold mode and is providing the output signal OUTPUT. Subsequently, during the time interval that the second sample and hold signal path SH2 is sampling the input signal INPUT (interval t_6 - t_7), the first sample and hold signal path SH1 is in its hold mode and is providing the output signal OUTPUT. Accordingly, temporally adjacent signals within the multiplexed output signal OUTPUT represent temporally adjacent samples of the input signal INPUT. Similarly, temporally coincident signals from the sample and hold signal paths SH1, SH2 also represent temporally adjacent samples of the input signal INPUT.

Switches SW1-SW7 have been represented in Figure 1 as single pole, single throw (SPST) switches. In a preferred embodiment, each of the switches SW1-SW7 is implemented in the form of a transmission gate, which consists of two pass transistors (a P-MOSFET and an N-MOSFET) with common drain terminal and common source terminal connections. However, it should be understood that switches SW1-SW6 can be implemented in other than SPST form. For example, switches SW1 and SW2 together can be implemented as a single pole, double throw (SPDT) switch with the pole connected to the output of the differential amplifier DA and one throw connected to each of the hold capacitors C_{H1} , C_{H2} .

Similarly, switches SW3 and SW4 together can be implemented as a SPDT switch with the pole connected to the output and each throw connected to an output of one of the buffering amplifiers A1, A2. Further similarly, switches SW5 and SW6 can be implemented as a SPDT switch with the pole connected to capacitor C_{C2} and switch SW7 and each throw connected to an output of one of the buffer amplifiers A1, A2. Alternatively, with appropriate timing adjustments for their respective switch control signals SW1-SW4, each of these switch pairs SW1/SW2, SW3/SW4, SW5/SW6 can also be implemented in the form of a multiplexor.

Referring to Figure 4, a number of pipelined sample and hold signals with correlated double circuits in accordance with the present invention can be interconnected via a network of switches SWA, SWB, SWC ... and SWAB, SWBC, SWCD ... to provide for combining, or "binning," of input signals A, B, C ... from multiple pre-amplifiers. The serial input switches SWA, SWB, SWC ... are used for disconnecting those sampling circuits which are to be disabled during the "binning" mode, while the shunting input switches SWAB, SWBC, SWCD ... are used for selectively interconnecting the input channels A, B, ... to the sampling circuit to be used in the binning mode. Cancellation of the pre-amplifier reset noise occurs as discussed above, but through one sampling circuit instead of multiple sampling circuits.

Accordingly, for example, for binning signals from two channels (A and B), switches SWA, SWB and SWAB would be closed and input signals A and B would be coupled into sampling circuit A via their respective input coupling capacitors C_{ClA} and C_{ClB} , while switches SWB, SWC, SWBC and SWCD would be open. As should be evident, this binning technique can be extended to any number of channels.

Various other modifications and alterations in the structure and method of operation of this invention will be apparent to those skilled in the art without departing from the scope and spirit of the invention. Although the invention has been described in connection with specific preferred embodiments, it should be understood that the invention as claimed should not be unduly limited to such specific embodiments. It is intended that the following claims define the scope of the present invention and that structures and methods within the scope of these claims and their equivalents be covered thereby.

WHAT IS CLAIMED IS:

1. An apparatus including a signal sampling circuit for performing correlated double sampling (CDS) of an input signal with a pipelined sample and hold architecture, said signal sampling circuit
5 comprising:

a capacitive input circuit configured to receive an input signal and in accordance therewith provide a capacitively coupled input signal, wherein said input signal includes a desired signal component and an undesired signal component;

10 a differential amplifier, coupled to said capacitive input circuit and including first and second input terminals and an output terminal, configured to receive said capacitively coupled input signal and a reference voltage via said first and second differential amplifier input terminals, respectively, and in accordance therewith provide an amplified input signal via said differential amplifier output terminal;

15 a pipelined sample and hold circuit, coupled to said differential amplifier output terminal, configured to receive a plurality of sampling control signals and in accordance therewith receive, sample and hold said amplified input signal and in accordance therewith provide first and second pluralities of time multiplexed input signal samples, wherein respective temporally adjacent ones of said first and second pluralities of time multiplexed input signal samples and temporally coincident ones of said first and second pluralities of time
20 multiplexed input signal samples represent temporally adjacent samples of said input signal; and

a capacitive feedback circuit, coupled between said pipelined sample and hold circuit and said first differential amplifier input terminal, configured to receive a feedback control signal and in accordance therewith receive said first plurality of time multiplexed input signal
25 samples, wherein said first and second pluralities of time multiplexed input signal samples include said desired signal component and exclude said undesired signal component.

2. The apparatus of claim 1, wherein:

30 said first and second input terminals of said differential amplifier comprise inverting and noninverting input terminals of said differential amplifier, respectively; and

said differential amplifier, said pipelined sample and hold circuit and said capacitive feedback circuit together comprise a time multiplexed integrating amplifier circuit.

3. The apparatus of claim 1, wherein said pipelined sample and hold circuit comprises:

5 a first signal selector circuit configured to receive a first portion of said plurality of sampling control signals and in accordance therewith receive and sample said amplified input signal and in accordance therewith provide a plurality of time multiplexed samples of said amplified input signal;

10 a plurality of shunt capacitors, coupled to said first signal selector circuit, configured to receive said plurality of time multiplexed samples of said amplified input signal and in accordance therewith provide a plurality of held samples of said amplified input signal; and

15 a second signal selector circuit, coupled to said plurality of shunt capacitors, configured to receive a second portion of said plurality of sampling control signals and in accordance therewith receive and select among said held samples of said amplified input signal and in accordance therewith provide said first and second pluralities of time multiplexed input signal samples.

4. The apparatus of claim 3, wherein said first and second signal selector circuits comprise first and second pluralities of pass transistors.

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5. The apparatus of claim 1, wherein said capacitive feedback circuit comprises:

a capacitor configured to alternately charge and discharge, wherein said capacitor charging is in accordance with said first plurality of time multiplexed input signal samples; and

25 a switch, coupled across said capacitor, configured to receive said feedback control signal and in accordance therewith alternately allow said charging and cause said discharging of said capacitor.

6. An apparatus including a signal sampling circuit for performing correlated double sampling (CDS) of an input signal with a pipelined sample and hold architecture, said signal sampling circuit
30 comprising:

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a capacitive input circuit configured to receive an input signal and in accordance therewith provide a capacitively coupled input signal, wherein said input signal includes a desired signal component and an undesired signal component;

5 a differential amplifier, coupled to said capacitive input circuit and including first and second input terminals and an output terminal, configured to receive said capacitively coupled input signal and a reference voltage via said first and second differential amplifier input terminals, respectively, and in accordance therewith provide an amplified input signal via said differential amplifier output terminal;

10 a pipelined sample and hold circuit, coupled to said differential amplifier output terminal, configured to receive one or more sampling control signals and in accordance therewith receive, sample and hold said amplified input signal and in accordance therewith provide a plurality of input signal samples and to time multiplex said plurality of input signal samples and in accordance therewith provide a first plurality of time multiplexed input signal samples, wherein temporally coincident ones of said plurality of input signal samples and
15 temporally adjacent ones of said first plurality of time multiplexed input signal samples represent temporally adjacent samples of said input signal; and

a capacitive switching feedback circuit, coupled between said pipelined sample and hold circuit and said first differential amplifier input terminal, configured to receive a plurality of feedback control signals and said plurality of input signal samples and in accordance therewith
20 time multiplex said plurality of input signal samples and in accordance therewith provide a second plurality of time multiplexed input signal samples and to charge and discharge in accordance therewith, wherein said first and second pluralities of time multiplexed input signal samples include said desired signal component and exclude said undesired signal component.

25 7. The apparatus of claim 6, wherein:

said first and second input terminals of said differential amplifier comprise inverting and noninverting input terminals of said differential amplifier, respectively; and

said differential amplifier, said pipelined sample and hold circuit and said capacitive switching feedback circuit together comprise a time multiplexed integrating amplifier circuit.

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8. The apparatus of claim 6, wherein said pipelined sample and hold circuit comprises:

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a first signal selector circuit configured to receive a first portion of said one or more sampling control signals and in accordance therewith receive and sample said amplified input signal and in accordance therewith provide a plurality of time multiplexed samples of said amplified input signal;

5 a plurality of shunt capacitors, coupled to said first signal selector circuit, configured to receive said plurality of time multiplexed samples of said amplified input signal and in accordance therewith provide a plurality of held samples of said amplified input signal; and

a second signal selector circuit, coupled to said plurality of shunt capacitors, configured to receive a second portion of said one or more sampling control signals and in accordance therewith receive and select among said held samples of said amplified input signal and in
10 accordance therewith provide said first plurality of time multiplexed input signal samples.

9. The apparatus of claim 8, wherein said first and second signal selector circuits comprise first and second pluralities of pass transistors.

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10. The apparatus of claim 6, wherein said capacitive switching feedback circuit comprises:

a third signal selector circuit configured to receive a first portion of said plurality of feedback control signals and in accordance therewith receive and time multiplex said plurality of input signal samples and in accordance therewith provide said second plurality of time
20 multiplexed input signal samples;

a capacitor, coupled to said third signal selector circuit, configured to receive said second plurality of time multiplexed input signal samples and alternately charge and discharge, wherein said capacitor charging is in accordance with said second plurality of time multiplexed input signal samples; and

25 a switch, coupled across said capacitor, configured to receive a second portion of said plurality of feedback control signals and in accordance therewith alternately allow said charging and cause said discharging of said capacitor.

11. The method of claim 10, wherein said third signal selector circuit comprises a plurality of
30 pass transistors.

12. A method of performing correlated double sampling (CDS) of an input signal with pipelined sampling and holding, said method comprising the steps of:

- 5 (a) receiving and capacitively coupling an input signal and in accordance therewith generating a capacitively coupled input signal, wherein said input signal includes a desired signal component and an undesired signal component;
- (b) receiving said capacitively coupled input signal and a reference voltage via first and second input terminals, respectively, of a differential amplifier and in accordance therewith generating an amplified input signal via an output terminal of said differential amplifier;
- 10 (c) receiving a plurality of sampling control signals and in accordance therewith sampling and holding said amplified input signal and in accordance therewith generating first and second pluralities of time multiplexed input signal samples, wherein respective temporally adjacent ones of said first and second pluralities of time multiplexed input signal samples and temporally coincident ones of said first and second pluralities of time multiplexed input signal samples represent temporally adjacent samples of said input signal; and
- 15 (d) receiving a feedback control signal and in accordance therewith capacitively coupling said first plurality of time multiplexed input signal samples to said first differential amplifier input terminal, wherein said first and second pluralities of time multiplexed input signal samples include said desired signal component and exclude said undesired signal component.
- 20

13. The method claim 12, wherein said steps (b), (c) and (d) together comprise a method of performing a time multiplexed integration of said input signal.

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14. The method of claim 12, wherein said step (c) comprises:

receiving a first portion of said plurality of sampling control signals and in accordance therewith sampling said amplified input signal and in accordance therewith generating a plurality of time multiplexed samples of said amplified input signal;

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capacitively holding said plurality of time multiplexed samples of said amplified input signal and in accordance therewith generating a plurality of held samples of said amplified input signal; and

5 receiving a second portion of said plurality of sampling control signals and in accordance therewith selecting among said held samples of said amplified input signal and in accordance therewith generating said first and second pluralities of time multiplexed input signal samples.

15 15. The method of claim 12, wherein said step (d) comprises:

10 charging a capacitor in accordance with said first plurality of time multiplexed input signal samples; and

discharging said capacitor in accordance with said feedback control signal.

16. A method of performing correlated double sampling (CDS) of an input signal with pipelined
15 sampling and holding, said method comprising the steps of:

(a) receiving and capacitively coupling an input signal and in accordance therewith generating a capacitively coupled input signal, wherein said input signal includes a desired signal component and an undesired signal component;

20 (b) receiving said capacitively coupled input signal and a reference voltage via first and second input terminals, respectively, of a differential amplifier and in accordance therewith generating an amplified input signal via an output terminal of said differential amplifier;

25 (c) receiving one or more sampling control signals and in accordance therewith sampling and holding said amplified input signal and in accordance therewith generating a plurality of input signal samples, wherein temporally coincident ones of said plurality of input signal samples represent temporally adjacent samples of said input signal;

30 (d) time multiplexing said plurality of input signal samples and in accordance therewith generating a first plurality of time multiplexed input signal samples, wherein temporally adjacent ones of said first plurality of time multiplexed input signal samples represent temporally adjacent samples of said input signal; and

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- (e) receiving a first portion of a plurality of feedback control signals and in accordance therewith time multiplexing said plurality of input signal samples and in accordance therewith generating a second plurality of time multiplexed input signal samples; and
- (f) receiving a second portion of said plurality of feedback control signals and in accordance therewith capacitively coupling said second plurality of time multiplexed input signal samples to said first differential amplifier input terminal, wherein said first and second pluralities of time multiplexed input signal samples include said desired signal component and exclude said undesired signal component.

10 17. The method of claim 16, wherein said steps (b), (c), (d), (e) and (f) together comprise a method of performing a time multiplexed integration of said input signal.

18. The method of claim 16, wherein said step (c) comprises:

15 receiving a first portion of said one or more sampling control signals and in accordance therewith sampling said amplified input signal and in accordance therewith generating a plurality of time multiplexed samples of said amplified input signal; and

capacitively holding said plurality of time multiplexed samples of said amplified input signal and in accordance therewith generating a plurality of held samples of said amplified input signal.

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19. The method of claim 18, wherein said step (d) comprises:

receiving a second portion of said one or more sampling control signals and in accordance therewith selecting among said held samples of said amplified input signal and in accordance therewith generating said first plurality of time multiplexed input signal samples.

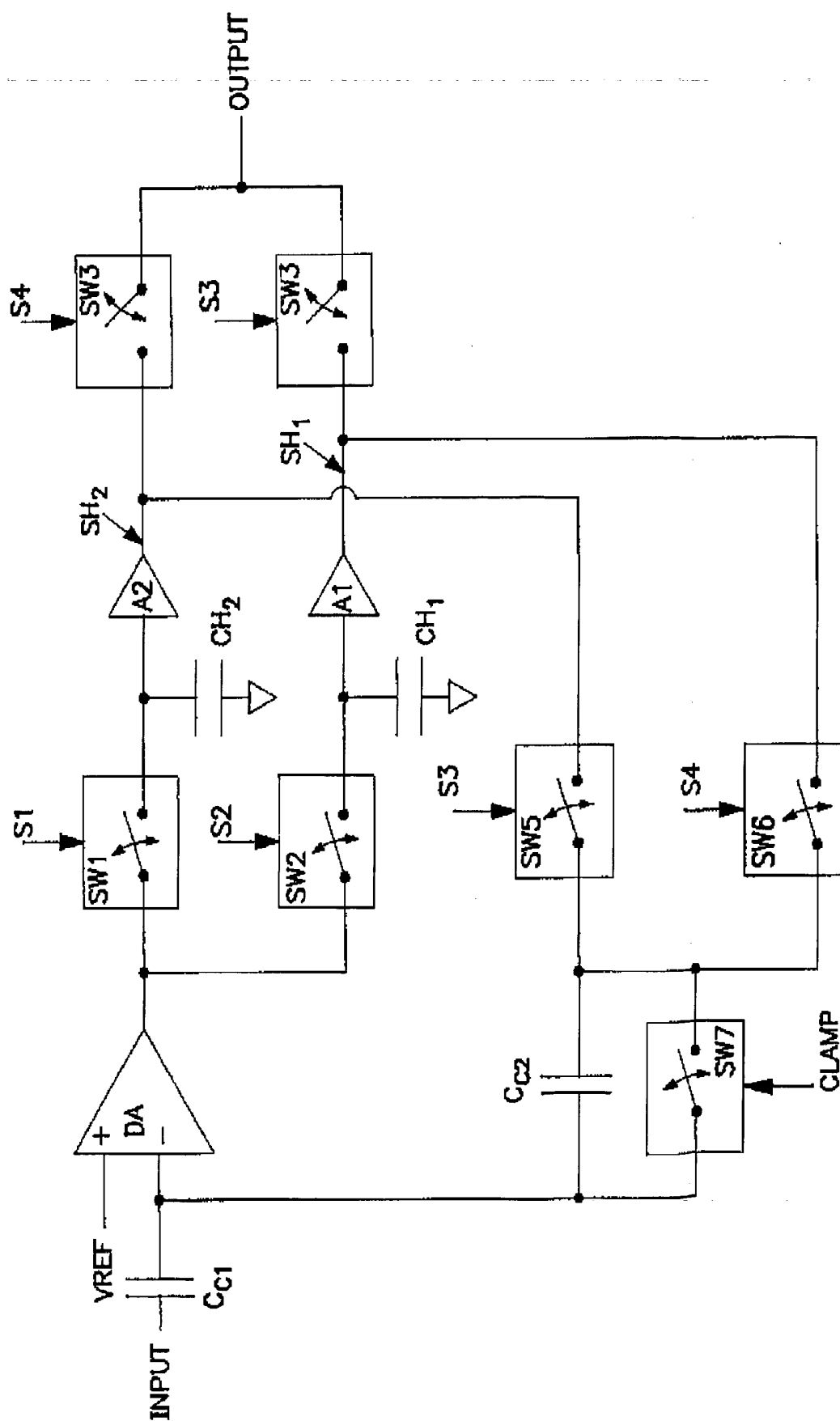
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20. The method of claim 16, wherein said step (f) comprises:

charging a capacitor in accordance with said second plurality of time multiplexed input signal samples; and

30 discharging said capacitor in accordance with said second portion of said plurality of feedback control signals.

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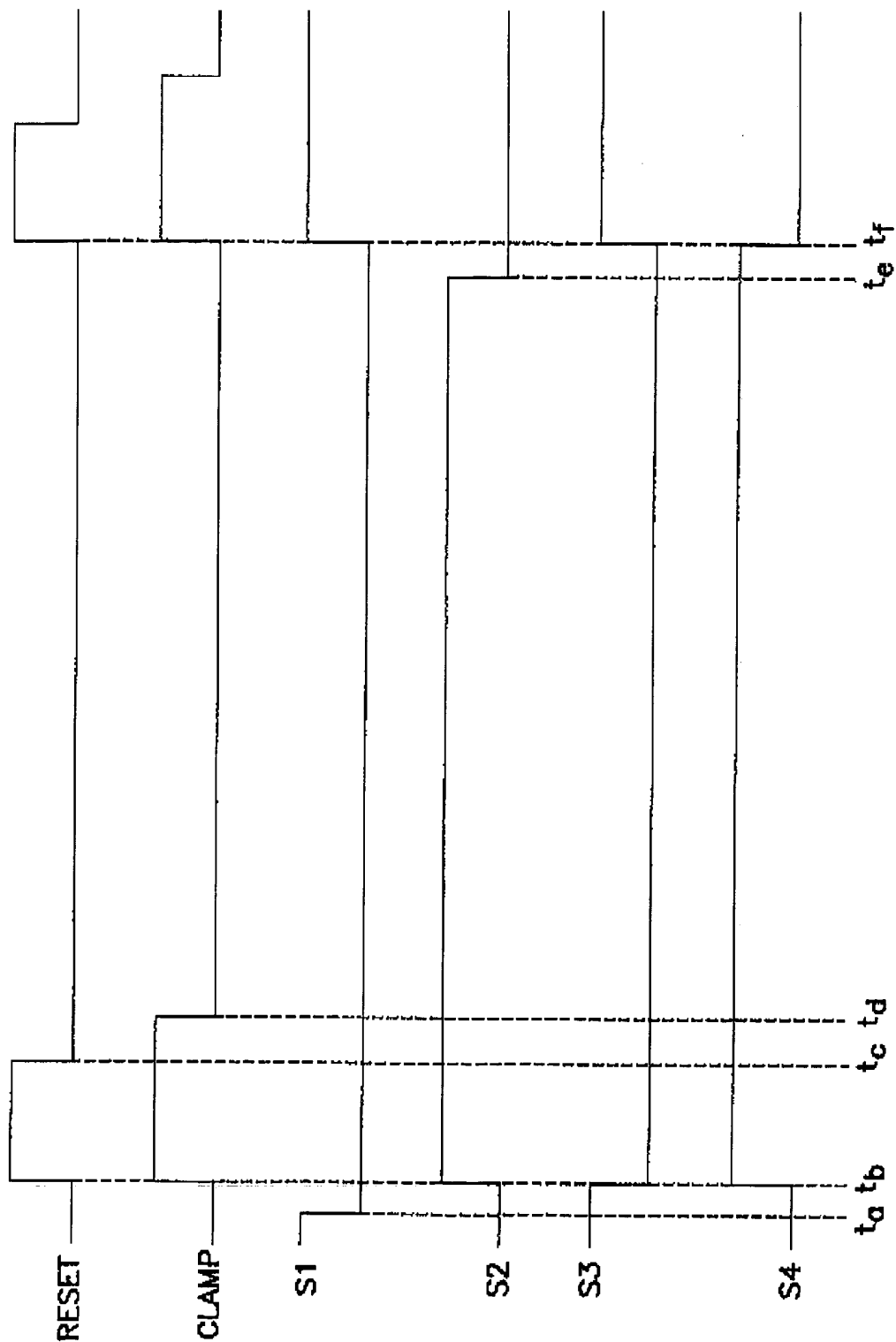


FIG. 2

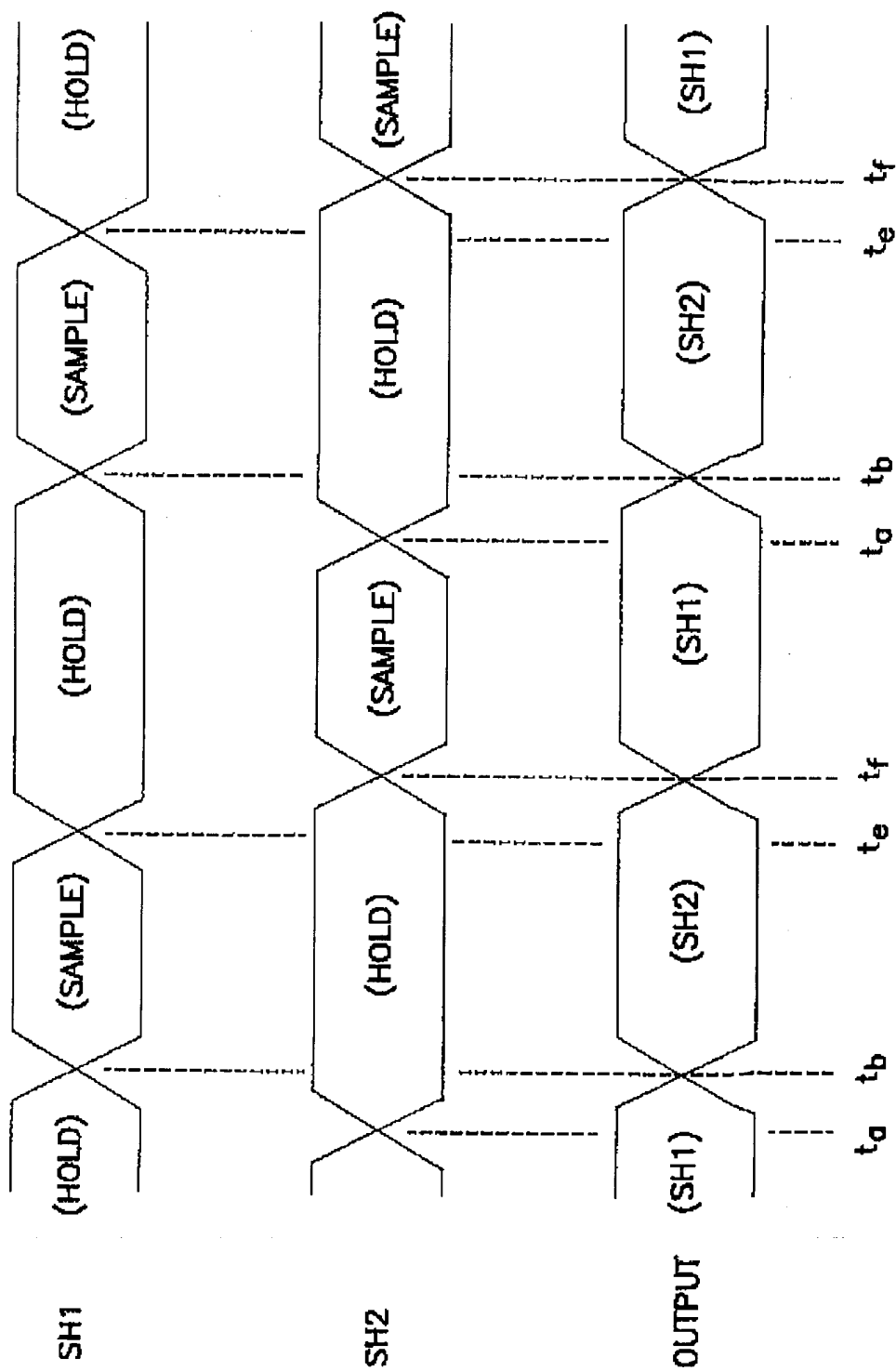


FIG. 3

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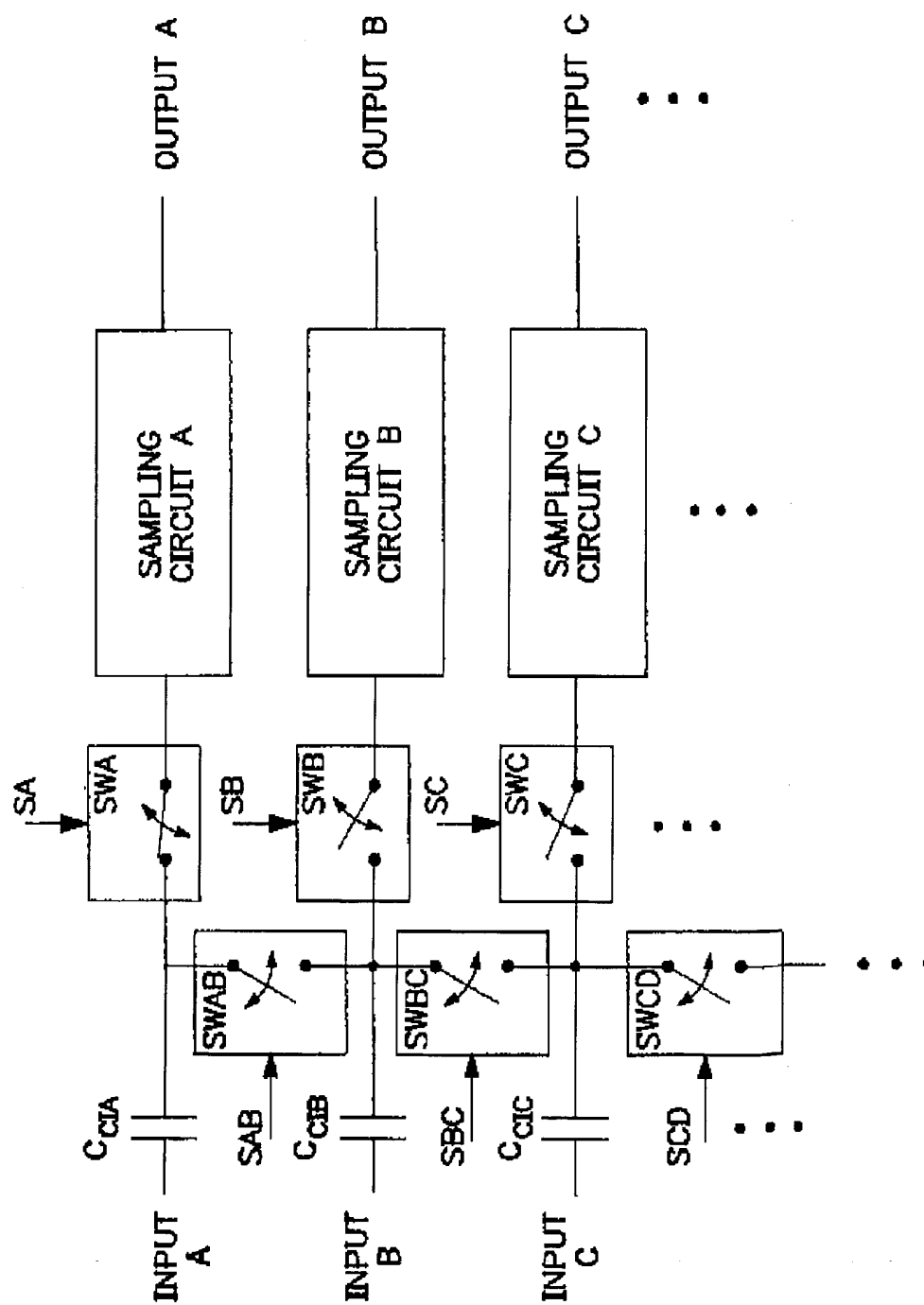


FIG. 4

INTERNATIONAL SEARCH REPORT

In. tional Application No

PCT/US 97/21164

A. CLASSIFICATION OF SUBJECT MATTER
IPC 6 G11C27/02

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 6 G11C

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 4 585 956 A (LIE HANS P) 29 April 1986 see column 1, line 13-54; figure 1 see column 3, line 20 - column 4, line 57; figures 2-4 ---	1-4, 6-9, 12-14, 16-19
A	EP 0 217 284 A (TOKYO SHIBAURA ELECTRIC CO ;TOSHIBA MICRO COMPUTER ENG (JP)) 8 April 1987 see abstract see column 2, line 16-40; figures 3,5 ---	5,10,11
A	EP 0 715 153 A (NIPPON ELECTRIC CO) 5 June 1996 -----	

☐ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

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Date of the actual completion of the international search:

16 March 1998

Date of mailing of the international search report

24/03/1998

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INTERNATIONAL SEARCH REPORT

Information on patent family members

Int. Patent Application No.

PCT/US 97/21164

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
US 4585956 A	29-04-86	CA 1207036 A	01-07-86
		EP 0107337 A	02-05-84
		GB 2128434 A,B	26-04-84
		JP 1801609 C	12-11-93
		JP 5007800 B	29-01-93
		JP 59082699 A	12-05-84
EP 0217284 A	08-04-87	JP 1746723 C	25-03-93
		JP 4034239 B	05-06-92
		JP 62076099 A	08-04-87
		US 4728811 A	01-03-88
EP 0715153 A	05-06-96	JP 2561040 B	04-12-96
		JP 8145717 A	07-06-96
		DE 69500956 D	04-12-97
		US 5633594 A	27-05-97